

DesignCon 2020 IBIS Summit
Santa Clara, California
January 31st, 2020

The On Die De-cap Modeling Proposal (BIRD198)

JEITA

Semiconductor & System Design Technical Committee

Semiconductor Design Technology Subcommittee

Presenter : Genichi Tanaka (Renesas Electronics Corporation)

Co-Authors: Atsushi Tomishima (Toshiba Electronic Devices & Storage Corporation)

Megumi Ono (Socionext Inc.)



Agenda

- Background
- Proposal for On Die De-cap Model
- Feedback and Updating
- Conclusion

Agenda

- **Background**
- Proposal for On Die De-cap Model
- Feedback and Updating
- Conclusion

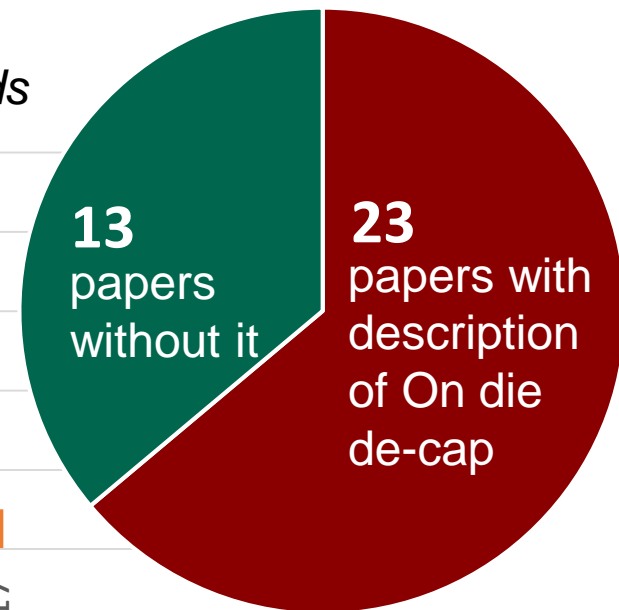
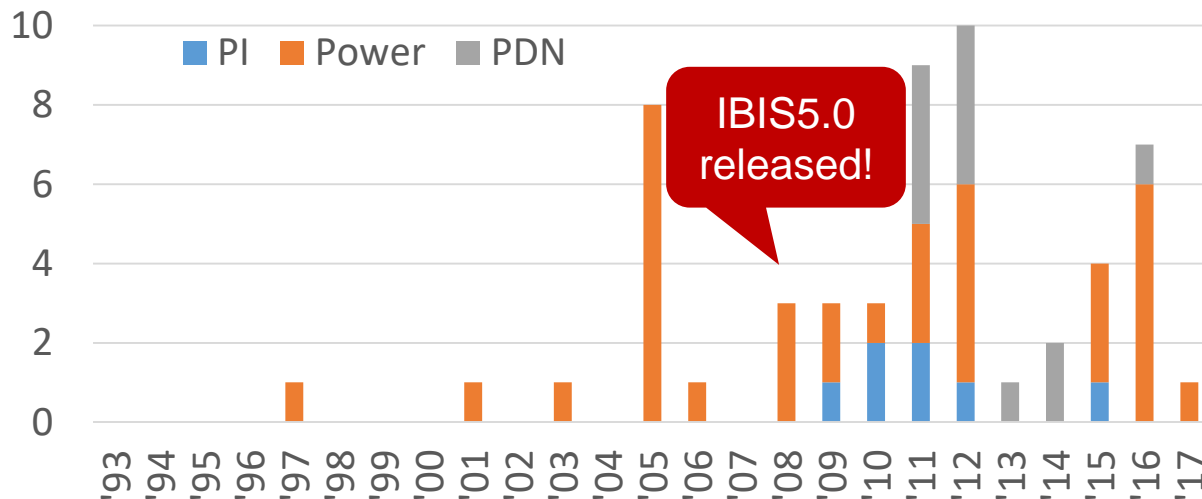
Chip PDN Characteristic

■ Chip PDN characteristic

- **On die resistance** affects IR-Drop and Q factor
- **On die de-cap** affects high frequency power-supply noise

Many papers reported in IBIS Summit describe importance of **On die de-cap**, because it is one of the few solutions to reduce high frequency power-supply noise

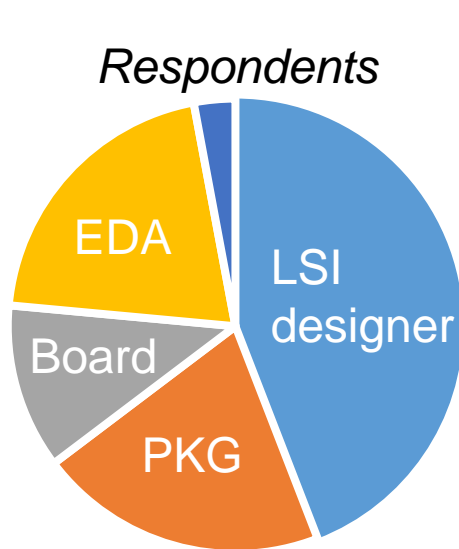
The titles of IBIS Summit papers have the following words



A Survey of On Die De-cap Model

- However, board and system designers can hardly obtain On die de-cap model

A Survey by JEITA LPB-SC MDL-WG @LPB developers workshop 2017.9.2

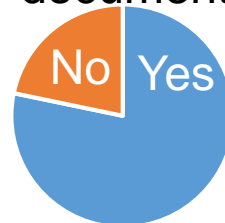


Q1. to All

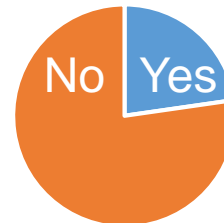
“Can you obtain information about Chip PDN?”

Answer

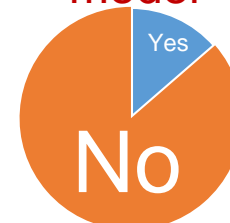
Guideline documents



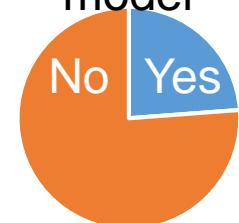
Target Z



On die de-cap model



PKG PDN model



Q2. to LSI designer

“What are you concerned about when you offer PDN model”

Answer

“Which model format is suitable for our customer?”

History of Our Proposal

Nov. 17, 2017 Asian IBIS Summit Tokyo, JAPAN

Proposal(Draft1)

Asian IBIS Summit
Tokyo, JAPAN
November 17, 2017

On die De-cap Modelin

Murata Kazuki (RICOH COM
JEITA

Semiconductor & System Design T
LPB Interoperable Design Su
Modeling Working G



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<https://ibis.org/summits/nov17c/murata.pdf>

Sep. 8, 2018 LPB workshop

Proposal(Draft2)

オンチップデキャップ考慮の
必要性と測定方法

坂田和之 (ルネサスエレクトロニクス)、村田和之
JEITA半導体&システム設計技術委員
LPB相互設計サブコミッティ
モデリングワーキンググループ



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Feb. 1, 2019 DesignCon 2019 IBIS Summit

Proposal(Final)

DesignCon 2019 IBIS Summit
Santa Clara, CA
February 1, 2019

On Die De-cap Modeling Proposal

Kazuki Murata (Ricoh Co.,Ltd.), Megumi Ono (Socionext Inc.)
JEITA
Semiconductor & System Design Technical Committee
LPB Interoperable Design Sub-Committee
Modeling Working Group



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<https://ibis.org/summits/feb19/murata.pdf>



History of Our Proposal

March 11, 2019: Submitted <https://ibis.org/birds/>

Buffer Issue Resolution Documents (BIRD)

To submit a BIRD to the IBIS Open Forum, please use the [BIRD Template, Rev. 1.3](#).

| ID# | Issue Title | Requester | Date Submitted | Date Accepted | Supporting Version |
|-----|--|---|----------------|--------------------|--------------------|
| 200 | C_comp Model Using IBIS-ISS or Touchstone | Randy Wolff, Micron Technology, Inc. Walter Katz, Signal Integrity Software, Inc. | July 9, 2019 | September 27, 2019 | |
| 199 | Fix Rx Receiver Sensitivity Inconsistencies | Arpad Muranyi, Mentor a Siemens Business | March 19, 2019 | June 7, 2019 | |
| 198 | Keyword additions for On Die PDN (Power Distribution Network) Modeling | Kazuki Murata; Ricoh Co., Ltd.; Miyoko Goto; Ricoh Co., Ltd.; Kazuyuki Sakata; Renesas Electronics Corporation; Kazunori Yamada; Renesas Electronics Corporation; Kouji Ichikawa; Denso Corporation; Atsushi Tomishima; Toshiba Electronic Devices & Storage Corporation; Takashi Hasegawa; Sony LSI Design Inc.; Koichi Seko, Panasonic Industrial Devices Systems and Technology Co., Ltd.; Toshiki Kanamoto; Hirotsaki University Megumi Ono; Socionext Inc. | March 11, 2019 | | |

IBIS Specification Change Template, Rev. 1.3^v

BUFFER ISSUE RESOLUTION DOCUMENT (BIRD)-

BIRD NUMBER: 198^v
ISSUE TITLE: Keyword additions for On Die PDN (Power Distribution Network) Modeling^v
REQUESTOR: Kazuki Murata, Ricoh Co., Ltd.^v
Miyoko Goto, Ricoh Co., Ltd.^v
Kazuyuki Sakata, Renesas Electronics Corporation^v
Kazunori Yamada, Renesas Electronics Corporation^v
Kouji Ichikawa, Denso Corporation^v
Atsushi Tomishima, Toshiba Electronic Devices & Storage Corporation^v
Takashi Hasegawa, Sony LSI Design Inc.^v
Koichi Seko, Panasonic Industrial Devices Systems and Technology Co., Ltd.^v
Toshiki Kanamoto, Hirotsaki University^v
Megumi Ono, Socionext Inc.^v

DATE SUBMITTED: March 11, 2019^v
DATE REVISIED: ^v
DATE ACCEPTED: ^v

DEFINITION OF THE ISSUE:^v
To resolve the power-supply noise issue, especially high frequency range, on die decap should be taken account into the simulation. With current IBIS versions, "On Die PDN" can be defined by using the keyword [Series Pin Mapping] and "Model_type Series".^v
However, this method seems not to be widely recognized, because the keyword [Series Pin Mapping] and "Model_type Series" don't make imagine to describe the on die PDN model. To ease usage of "On Die PDN" in the IBIS model, this BIRD proposes to add the new keywords [PDN Model Mapping], "Model_type PDN", [C pdn], [R pdn], [R leak], [C pdn corner], [R pdn corner] and [R leak corner] for PDN model only.^v

SOLUTION REQUIREMENTS:^v
The IBIS specification must meet these requirements:^v

• Table 1: Solution Requirements.

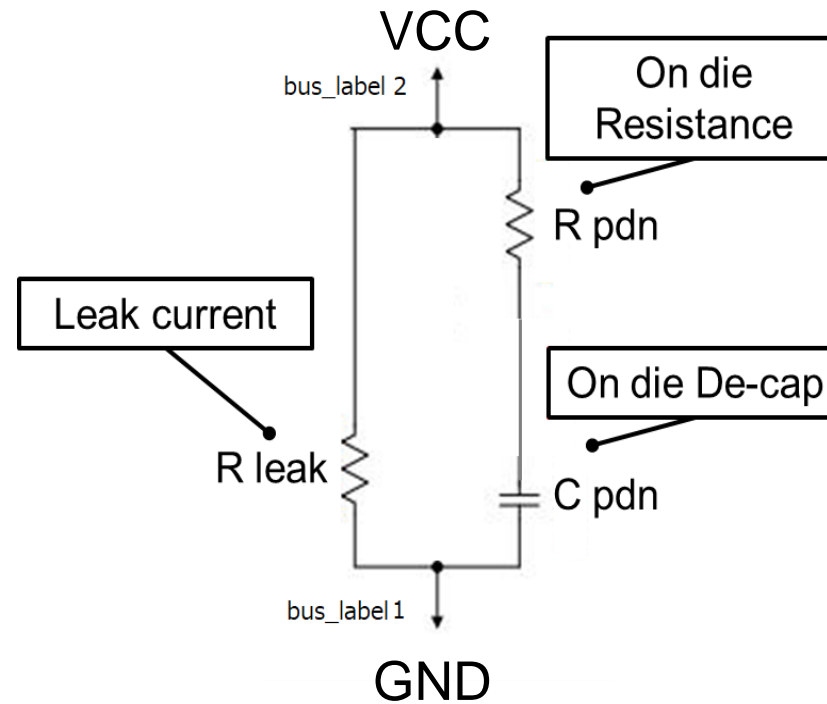
| Requirement ^v | Notes ^v |
|---|--------------------|
| 1. A new keyword is defined under [Component] ^v [PDN Model Mapping] ^v | ^v |
| 2. A new sub parameter is defined under [Model]: "Model_type PDN" ^v | ^v |

Agenda

- Background
- **Proposal for On Die De-cap Model**
- Feedback and Updating
- Conclusion

Proposal

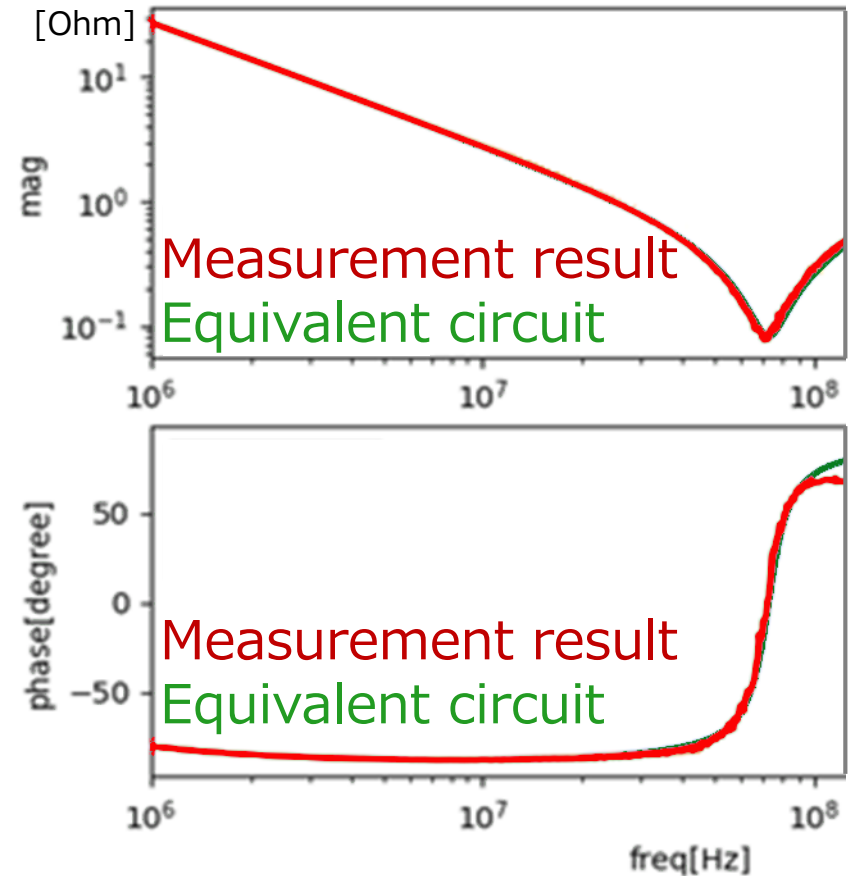
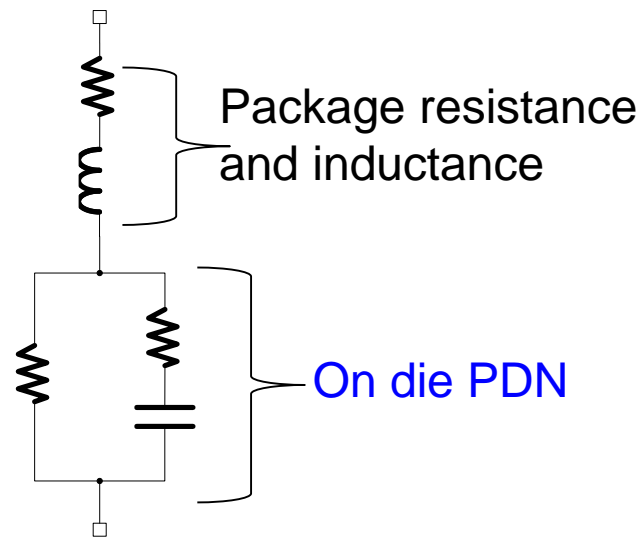
Model



Correlation between Measurement and Model

- Our proposed model is correlated with the measurement results.

Equivalent circuit



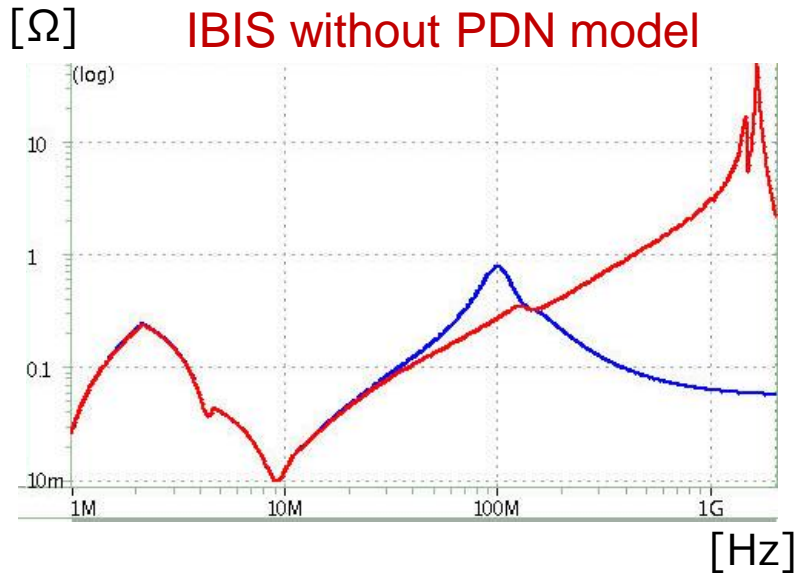
Simulation Results

- Simulation results using the proposed IBIS model

AC analysis result
= PDN input impedance

IBIS with PDN model

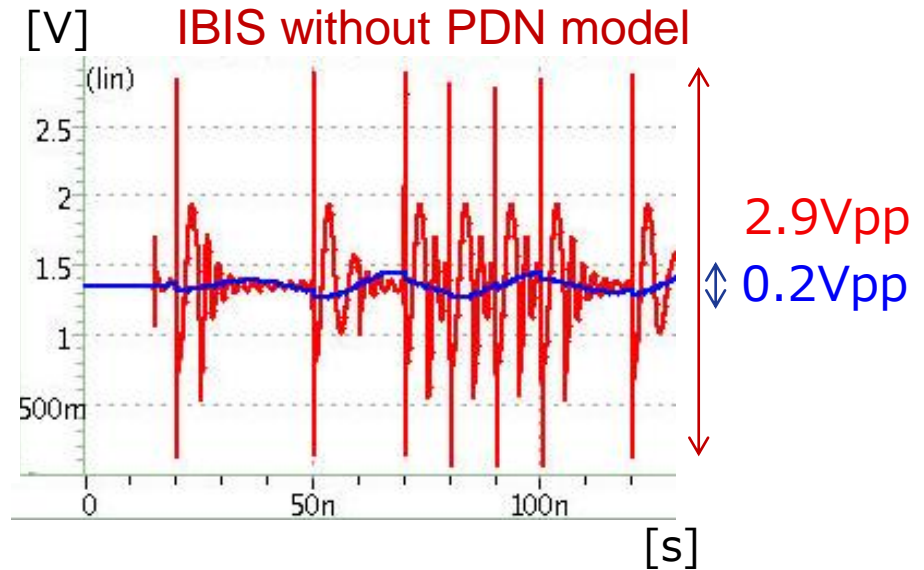
IBIS without PDN model



Transient analysis result
= IO switching VDD noise @DIE

IBIS with PDN model

IBIS without PDN model



- The expected result was obtained while using a simulator

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Original vs. Latest

| | BIRD198 Original | Latest proposal | Latest feedback from ATM task group |
|------------------------|--|--|---|
| Connection | Pin | Bus_label | Bus_label or signal_name |
| Parent | [Model] | [Component] | [Component] |
| Model selecting Method | ✓ [Model Selector] | ✓ New method [PDN Domain]& [PDN Model] | ✓ New method [PDN Domain]& [PDN Model] |
| Corner definition | ✓ The order of the values is not related to magnitude | ✓ The order of the values is not related to magnitude Naming Rule : C_pdn_case R_pdn_case R_leak_case | ✓ The order of the values is not related to magnitude Naming Rule : C_pdn R_pdn R_leak |
| Base structure | Series Model | New syntax | New syntax |
| EDA Vendor | Difficult implementation | Easy implementation | Easy implementation |

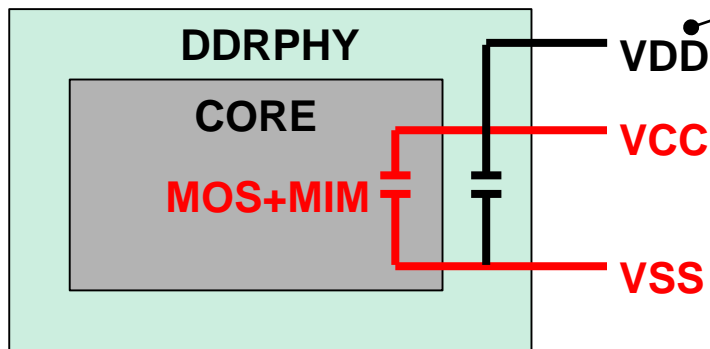
Latest Proposal

| | BIRD198 Original | Latest proposal | Latest feedback from ATM task group |
|------------------------|--|--|---|
| Connection | Pin | Bus_label | Bus_label or signal_name |
| Parent | [Model] | [Component] | [Component] |
| Model selecting Method | ✓ [Model Selector] | ✓ New method [PDN Domain]& [PDN Model] | ✓ New method [PDN Domain]& [PDN Model] |
| Corner definition | ✓ The order of the values is not related to magnitude | ✓ The order of the values is not related to magnitude Naming Rule : C_pdn_case R_pdn_case R_leak_case | ✓ The order of the values is not related to magnitude Naming Rule : C_pdn R_pdn R_leak |
| Base structure | Series Model | New syntax | New syntax |
| EDA Vendor | Difficult implementation | Easy implementation | Easy implementation |

Case Study (VCC-VSS)

■ Assuming that 'Chip-A' model has:

- ✓ Core circuit and core supply voltage VCC-VSS with MIM capacitor.
 - Capacitor by MOS depends on voltage range
 - Capacitor by MIM does not depend on MOS process
- ✓ DDR3/3L/4 combo PHY and PHY supply voltage VDD-VSS.
 - Capacitor by MOS depends on voltage range
 - Typical VDD voltage changes 1.5V, 1.35V or 1.2V due to mode.



| Mode | Typ. | Min | Max |
|-------|-------|--------|--------|
| DDR3 | 1.5V | 1.425V | 1.575V |
| DDR3L | 1.35V | 1.283V | 1.425V |
| DDR4 | 1.2V | 1.14V | 1.26V |

| Typ. | Min | Max |
|------|-------|-------|
| 1.0V | 0.95V | 1.05V |

Case Study (IBIS Syntax)

[PDN Domain] PDN_for_VCC

```
Rail_Bus_Labels VCC VSS
|VCC Voltage          1.0      0.9
|Temp.                25      125
|Mos                  TT      SS
```

The order of the columns do not matter at all.

[PDN Model] With_Medium_MIM

| | | | |
|-------------|-------|-------|-------|
| C_pdn_case | 270n | 220n | 320n |
| R_pdn_case | 2.18m | 2.67m | 0.98m |
| R_leak_case | 5k | 8k | 2k |

[End PDN Model]

[PDN Model] With_Large_MIM

| | | | |
|-------------|-------|-------|-------|
| C_pdn_case | 280n | 230n | 330n |
| R_pdn_case | 1.93m | 2.30m | 0.87m |
| R_leak_case | 5k | 8k | 2k |

[End PDN Model]

[PDN Model] With_Small_MIM

| | | | |
|-------------|-------|-------|-------|
| C_pdn_case | 260n | 210n | 310n |
| R_pdn_case | 2.31m | 2.86m | 1.01m |
| R_leak_case | 5k | 8k | 2k |

[End PDN Model]

[End PDN Domain]

Case Study (EDA Selects Value)

EDA example

```
.ibis syntax_a2
```

```
+ file = 'aaa.ibs'
```

```
+ component = 'ChipA'
```

```
+ typ = min * or slow
```

```
+ pdn_sel = 'PDN_for_VCC=With_Small_MIM,  
PDN_for_VDD=DDR3'
```

1.05

-40

320n

0.98m

2k

```
[PDN Model] With_Small_MIM
```

```
C_pdn_case      280n      230n
```

```
R_pdn_case      1.93m     2.30m
```

```
R_leak_case     5k         8k
```

```
[End PDN Model]
```

```
[PDN Model] With_Small_MIM
```

```
C_pdn_case      260n      210n      310n
```

```
R_pdn_case      2.31m     2.86m     1.01m
```

```
R_leak_case     5k         8k         2k
```

```
[End PDN Model]
```

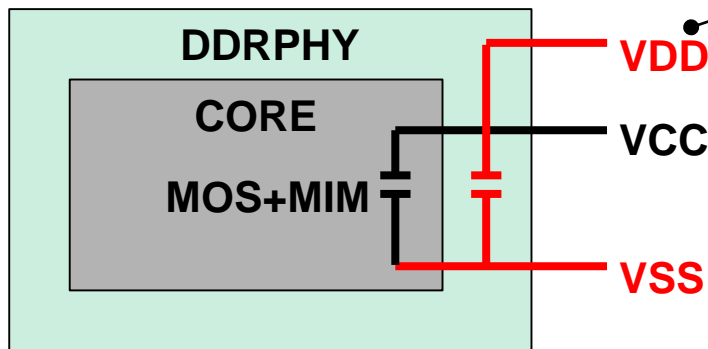
```
[End PDN Domain]
```

EDA
Selects
the values

Case Study (VDD-VSS)

■ Assuming that 'Chip-A' model has:

- ✓ Core circuit and core supply voltage VCC-VSS with MIM capacitor.
 - Capacitor by MOS depends voltage range
 - Capacitor by MIM does not depend MOS process
- ✓ DDR3/3L/4 combo PHY and PHY supply voltage VDD-VSS.
 - Capacitor by MOS depends on voltage range
 - Typical VDD voltage changes 1.5V, 1.35V or 1.2V due to mode.



| Mode | Typ. | Min | Max |
|-------|-------|--------|--------|
| DDR3 | 1.5V | 1.425V | 1.575V |
| DDR3L | 1.35V | 1.283V | 1.425V |
| DDR4 | 1.2V | 1.14V | 1.26V |

| Typ. | Min | Max |
|------|-------|-------|
| 1.0V | 0.95V | 1.05V |

Case Study (IBIS Syntax)

[PDN Domain] PDN_for_VDD

```
Rail_Bus_Labels VDD VSS
|VDD Voltage 1.5 1.425 1.575
```

[PDN Model] DDR3

```
C_pdn_case 5n 4n 6n
R_pdn_case 20m 30m 10m
R_leak_case 15k 17k 11k
```

[End PDN Model]

```
|VDD Voltage 1.35 1.283 1.425
```

[PDN Model] DDR3L

```
C_pdn_case 3n 2n 4.2n
R_pdn_case 20m 30m 10m
R_leak_case 15k 17k 11k
```

[End PDN Model]

```
|VDD Voltage 1.2 1.14 1.26
```

[PDN Model] DDR4

```
C_pdn_case 1.5n 1n 1.8n
R_pdn_case 20m 30m 10m
R_leak_case 15k 17k 11k
```

[End PDN Model]

[End PDN Domain]

Case Study (EDA Selects Value)

```
[PDN Domain] PDN_for_VDD
Rail_Bus_Labels VDD VSS
|VDD Voltage 1.5 1.425 1.575
[PDN Model] DDR3
C_pdn_case 5n 4n 6n
R_pdn_case 20m 30m 10m
R_leak_case 15k 17k 11k
[End PDN Model]
```

EDA example

.ibis syntax_a2

+ *file* = 'aaa.ibs'

+ *component* = 'ChipA'

+ *typ* = *min* * or *slow*

+ *pdn_sel* = 'PDN_for_VCC=With_Small_MIM,
PDN_for_VDD=DDR3'

[End PDN Model]

[End PDN Domain]

EDA
Selects
the values

6

1.8n
10m
11k

Latest Feedback

| | BIRD198 Original | Latest proposal | Latest feedback from ATM task group |
|------------------------|--|--|--|
| Connection | Pin | Bus_label | Bus_label or signal_name |
| Parent | [Model] | [Component] | [Component] |
| Model selecting Method | ✓ [Model Selector] | ✓ New method [PDN Domain]& [PDN Model] | ✓ New method [PDN Domain]& [PDN Model] |
| Corner definition | ✓ The order of the values is not related on magnitude | ✓ The order of the values is not related on magnitude Naming Rule : C_pdn_case R_pdn_case R_leak_case | ✓ The order of the values is not related on magnitude Naming Rule : C_pdn R_pdn R_leak |
| Base structure | Series Model | New syntax | New syntax |
| EDA Vendor | Difficult implementation | Easy implementation | Easy implementation |

Latest Feedback¹ from ATM Task Group

Changes to consider:

1. The Rail_Bus_labels subparameter should be changed to allow for declaration by bus_label or signal_name. Still scoped under [PDN Domain], possible syntax is:

```
Bus_label    VCC1 | the beginning letter is  
              upper case  
Signal_name  VSS
```

We could have separately as another set of terminals under a different [PDN Domain]:

```
Signal_name  VCC  
Signal_name  VSS
```

Note if VCC1 is a bus_label of VCC, than we have shorted all VCC terminals and there is no separate VCC1 terminal. All of this needs to be considered. Rules in Interconnect modeling may help describe this.

Also, this would be illegal because one is a self-referencing subset of the other:

```
Bus_label    VCC1  
Signal_name  VC
```

2. “_case” could be removed for the names of the “C_pdn, R_pdn, and R_leak” parameters for simplification.
3. The examples should show “1G” for R_leak, since only “G” is defined in Section 3.2 SYNTAX RULES as a valid scale factor. “g” is not defined as valid.
4. It is not necessary, but you might consider wrapping all [PDN Domain]/[End PDN Domain] sections within a [Begin PDN Domains]/[End PDN Domains] keyword pair. This simplifies scoping of the whole section under [Component]. Otherwise, you could write a rule requiring all [PDN Domain]/[End PDN Domain] sections be grouped together. Without a requirement, these sections could be spread out amongst other keyword sections under a [Component], making it difficult to read and parse.

Latest Feedback1 from ATM Task Group

Changes to consider:

1. The Rail_Bus_labels subparameter should be changed to allow for declaration by **bus_label or signal_name**.

Still scoped under [PDN Domain], possible syntax is:

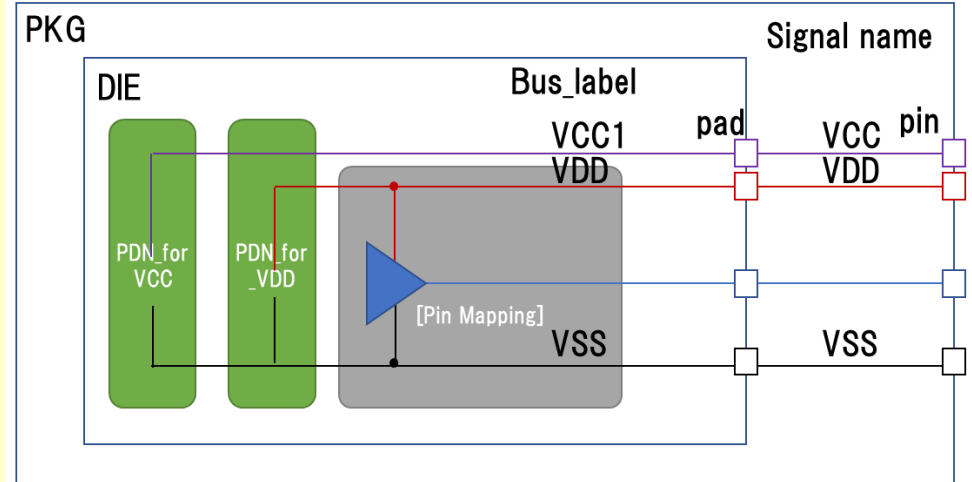
Bus_label VCC1 | the beginning letter is upper case
Signal_name VSS

We could have separately as another set of terminals under a different [PDN Domain]:

Signal_name VCC
Signal_name VSS

Case Study (IBIS Syntax)

```
[Component]      ChipA
[Pin]
  pin_A VCC POWER
  pin_B VDD POWER
  pin_C VSS GND
[Pin Mapping]
  pin_A      NC      VCC1
  pin_B      NC      VDD
  pin_C      VSS     NC
```



```
[PDN Domain] PDN_for_VCC
```

| A rail must be either a bus_label or a signal_name

```
Signal_name VCC
Signal_name VSS
```

| Alternately, if bus_label VCC1 is defined in [Pin Mapping]:

```
Bus_label VCC1
Signal_name VSS
```


Latest Feedback2 from ATM Task Group

Some rules to define with text and examples:

1. “NA” is allowed for slow/fast column values of C_pdn, R_pdn, and R_leak. This aligns with other parameters in IBIS. If the slow or fast column value is NA, then the EDA tool shall use the Typ value for simulation.
2. A PDN Model may contain:
 - a. C_pdn, R_pdn, and R_leak parameters
 - b. Only C_pdn and R_pdn parameters. R_leak is assumed to be a large value (e.g. 1G).
 - c. Only C_pdn and R_leak parameters. R_pdn is assumed to be a small value (e.g. 0.0).
 - d. Only C_pdn. R_pdn is assumed to be a small value (e.g. 0.0). R_leak is assumed to be a large value (e.g. 1G).
 - e. Only R_leak.
3. Allowed values for C_pdn, R_pdn, and R_leak parameters should be defined:
 - a. C_pdn shall be a non-negative number (positive or zero)
 - b. R_pdn shall be a non-negative number (positive or zero)
 - c. R_leak shall be a positive number (zero is not allowed)
4. [PDN Model] default selection rule should be defined. Example below mirrors the statement from [Model Selector]. The first [PDN Model] entry under the [PDN Domain] keyword shall be considered the default by the EDA tool.

Proposal from JEITA

We mostly agree 「ATM Task Group Proposal」.

2. A PDN Model may contain:
 - a. C_pdn, R_pdn, and R_leak parameters
 - b. Only C_pdn and R_pdn parameters. R_leak is assumed to be a large value (e.g. 1G).
 - c. Only C_pdn and R_leak parameters. R_pdn is assumed to be a small value (e.g. 0.0).
 - d. Only C_pdn. R_pdn is assumed to be a small value (e.g. 0.0).
R_leak is assumed to be a large value (e.g. 1G).
 - e. Only R_leak.



Our proposal is

“All parameters(C_pdn, R_pdn, and R_leak) must be defined.”

“The purser and EDA tool will give the error in case of the lack of definition”

| [PDN Model] | Legal_PDN | | |
|-----------------|-----------|-----------|-----------|
| C_pdn | 280n | 230n | 330n |
| R_pdn | 1.9m | 2.3m | 0.8m |
| R_leak | 1G | 1G | 1G |
| [End PDN Model] | | | |

| [PDN Model] | Not_legal_PDN | | |
|-----------------|---------------|------|------|
| C_pdn | 280n | 230n | 330n |
| R_pdn | 1.9m | 2.3m | 0.8m |
| [End PDN Model] | | | |

NOT LEGAL

Case Study (IBIS Syntax)

|R_leak = Open

```
[PDN Model] With Large MIM
      C_pdn      280n      230n      330n
      R_pdn      1.93m      2.30m      0.87m
      R_leak      1G          1G          1G
[End PDN Model]
```

|R_pdn = 0ohm

```
[PDN Model] With Large MIM
      C_pdn      280n      230n      330n
      R_pdn      0          0          0
      R_leak      5k        8k        2k
[End PDN Model]
```

|C_pdn = 0pF and R_pdn = 0ohm (Only R_leak) | (parser might issue warning about C_pdn = 0)

```
[PDN Model] With Large MIM
      C_pdn      0          0          0
      R_pdn      0          0          0
      R_leak      5k        8k        2k
[End PDN Model]
```

Agenda

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- Feedback and Updating
- **Conclusion**

Conclusion

Chip PDN model is still not widespread. Therefore, we proposed to add an **explicit keyword** of chip PDN to IBIS.

Our proposal was registered as BIRD198 and it has been discussed in IBIS Open Forum since this March 2019.

Thanks to the excellent discussion with the task group, the improved BIRD will be completed soon.

We plan to update BIRD198 to BIRD198.1 by March 13, 2020.

We expect that BIRD198.1 will be adopted and will be useful to many IBIS users.

Thank you!